

Notice of References Cited

Application/Control No.

09/808,325

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-5,983,381 | 11-1999 | Chakradhar et al. | 714/738 |
| | B | US-6,052,809 | 04-2000 | Bowden, Kenneth R. | 714/738 |
| | C | US-6,067,651 | 05-2000 | Rohrbaugh et al. | 714/738 |
| | D | US-2002/0059546 a1 | 05-2002 | Yonetoku, Hirofumi | 714/738 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Hsiao, M.S.; Rudnick, E.M.; Patel, J.H., Fast static compaction algorithms for sequential circuit test vectors, March 1999, IEEE Transactions on Computers, Volume: 48 Issue: 3, Page(s): 311 -322 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.